

FCC ID:2BA4J-TNC225R

Portable device

According to §15.247(e)(i) and §1.1307(b)(1), systems operating under the provisions of this section shall be operated in a manner that ensures that the public is not exposed to radio frequency energy level in excess of the Commission’s guidelines.

According to KDB447498 D01 General RF Exposure Guidance V06

The 1-g SAR and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation distances ≤ 50 mm are determined by:

$[(\text{max. power of channel, including tune-up tolerance, mW})/(\text{min. test separation distance, mm})] \cdot \sqrt{f(\text{GHZ})} \leq 3.0$ for 1-g SAR and ≤ 7.5 for 10-g extremity SAR, where:

- $f(\text{GHZ})$ is the RF channel transmit frequency in GHz
- Power and distance are rounded to the nearest mW and mm before calculation
- The result is rounded to one decimal place for comparison

When the minimum test separation distance is < 5 mm, a distance of 5 mm is applied to determine SAR test exclusion.

Modulation	Channel Freq. (GHz)	Conduct ed power (dBm)	Conducte d power (mW)	Tune-up power (dBm)	Max tune-up power (dBm)	Max tune-up power (mW)	Distance (mm)	Result calculation	SAR Exclusion threshold	SAR test exclusion
802.11b	2.412	8.4	6.92	8.5±1	9.5	8.91	<5	2.76834	3.00	YES
	2.437	8.31	6.78	8.5±1	9.5	8.91	<5	2.78264	3.00	YES
	2.462	8.39	6.90	8.5±1	9.5	8.91	<5	2.79688	3.00	YES
802.11g	2.412	8.17	6.56	8.5±1	9.5	8.91	<5	2.76834	3.00	YES
	2.437	8.31	6.78	8.5±1	9.5	8.91	<5	2.78264	3.00	YES
	2.462	8.33	6.81	8.5±1	9.5	8.91	<5	2.79688	3.00	YES
802.11n H20	2.412	7.97	6.27	8.5±1	9.5	8.91	<5	2.76834	3.00	YES
	2.437	8.22	6.64	8.5±1	9.5	8.91	<5	2.78264	3.00	YES
	2.462	8.42	6.95	8.5±1	9.5	8.91	<5	2.79688	3.00	YES
BLE 1M	2.402	1.47	1.40	2±1	3	2.00	<5	0.61847	3.00	YES
	2.440	1.88	1.54	2±1	3	2.00	<5	0.62334	3.00	YES
	2.480	2.05	1.60	2±1	3	2.00	<5	0.62843	3.00	YES

Conclusion:

For the max result : $2.79688 \leq 3.0$ for 1g SAR, SAR is not required.



Signature:

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